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James [NZ/NZ]; 11 Blencathra Place, Westmoreland, Christchurch (NZ). WILSON, Paul, Francis, [NZ/NZ]; 468 Durham Street North, Richmond, Christchurch 8001 (NZ).

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(74) Agent: WEST-WALKER, Nigel; P.O. Box 4, Picton 7372 (NZ).

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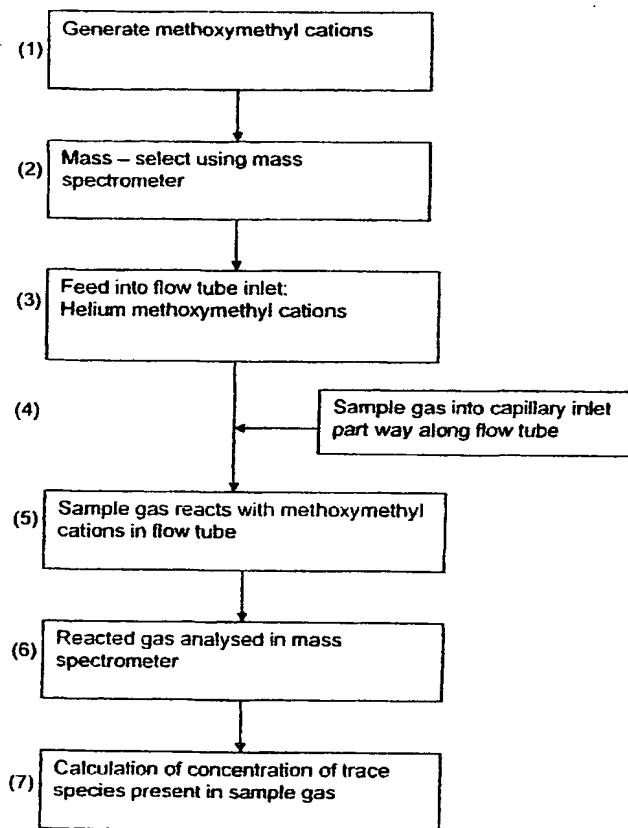
(71) Applicant (for all designated States except US): SYFT TECHNOLOGIES LIMITED [NZ/NZ]; 3 Craft Place, Middleton, Chrischurch (NZ).

(72) Inventors; and

(75) Inventors/Applicants (for US only): McEWAN, Murray,

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(54) Title: IMPROVED METHOD OF CHEMICAL IONIZATION MASS SPECTROMETRY



(57) Abstract: A method of detecting a substance present in a gas or a gas mixture using SIFT-MS technology comprising the steps of inducing a supply of alkoxymethyl cations into the inlet of the flow tube, reacting a sample of the as with the alkoxymethyl cations, analysing the reacted gas sample, and calculating the concentration of trace levels of molecules containing heteroatoms in the reacted gas sample.

WO 2004/006286 A1